JUNO datalog decoded

By Richard Morgan and Phil Mao from Diodes

as of Feb 4, 2014

All 2 byte numbers are stored in LSB-MSB order and negative numbers in two's compliment format.

General file header Section

[F:\ZXTN3035CLP-9R51WOVEN.1-19.jdf] - Frhed																	
<u>File Disk Edit View Options Registry Bookmarks Misc H</u> elp																	
🗅 🗃		<mark>ж</mark> Е	b 6	2	64	в	?										
000000	57	27	00	00	02	00	1a	00	00	41	06	18	00	00	01	00	• · · · · · · · · A · · · · · · •
000010	00	00	00	00	00	00	00	00	1 a	00	ff	ff	ff	03	00	00	ÿÿÿ 🥅
000020	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	
000030	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	
000040	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	
000050	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	
000060	00	00	00	00	00	00	00	00	4a	20	30	30	30	34	00	00	
000070	00	00	00	00	63	66	2e	20	64	65	76	69	63	65	2e	74	cf. device.t
000080	78	74	00	00	00	00	00	00	5a	58	54	4e	33	30	33	35	xtZXTN3035
000090	43	4c	50	2d	39	52	35	31	57	4f	56	45	63	66	2e	20	CLP-9R51WOVEcf.
0000a0	6f	70	65	72	61	74	6f	72	2e	74	78	74	00	00	00	00	operator.txt
0000b0	50	Зa	5c	5a	45	54	45	58	5c	5a	58	54	4e	33	30	33	P:\ZETEX\ZXTN303
0000c0	35	43	4c	50	2e	6a	74	66	00	00	00	00	00	00	00	00	5CLP.jtf
0000d0	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	
0000e0	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	
0000f0	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	
																	F.
Offset 0=	Offset 0=0x0 Bits=01010111 Unsigned: B:87,W:10071,L:10071 ANSI / OVR / L Size: 1130544																

00000-00003	number of devices tested
000004	unknown
000006	number of tests in routine
000008-00001f	unknown
000068-000073	tester name
000074-000087	device name
000088-00009b	lot name
00009C-0000af	operator name
0000b0-0000c7	test routine name
0001b0-0001c7	comment

<u>Variable</u>

Memory Location

Test Header Section

[F:\ZXTN3035CLP-9R51WOVEN.1-19.jdf] - Frhed																	
<u>File Disk Edit View Options Registry Bookmarks Misc Help</u>																	
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000200	53	45	4c	50	49	4e	00	00	00	00	20	00	a2	00	10	00	SELPIN
000210	1f	00	00	00	01	00	00	00	00	73	00	00	00	73	00	00	ss
000220	00	00	01	00	00	00	00	00	00	00	00	00	04	00	00	00	
000230	10	00	00	00	01	00	00	00	00	00	00	00	00	00	00	00	
000240	00	00	00	00	00	00	00	00	10	00	00	00	7c	00	00	00	
000250	43	4f	4e	54	00	00	00	00	00	00	56	0b	81	00	00	00	CONTV
000260	19	00	00	80	02	00	fa	00	09	73	00	00	00	73	00	00	úss
000270	00	00	10	01	03	02	00	00	49	42	00	00	00	00	64	00	IBd.
000280	08	41	28	6e	6f	6e	65	29	00	00	00	20	28	6e	6f	6e	.A(none) (non
000290	65	29	00	00	00	20	f1	d8	18	0d	d0	07	7c	0b	00	00	e) ñØÐ.
0002a0	49	45	42	00	00	00	00	00	00	00	41	07	26	00	00	10	IEBA.&
0002b0	19	00	00	a0	03	00	c 8	00	09	73	f4	01	0a	73	dc	00	ÈsôsÜ.
0002c0	0a	00	00	28	00	00	00	00	56	45	42	00	00	00	2c	01	(VEB,.
0002d0	0c	56	28	6e	6f	6e	65	29	00	00	00	20	28	6e	6f	6e	.v(none) (non
0002e0	65	29	00	00	00	20	f1	d8	18	09	e8	03	7c	07	00	00	e) ñøè.
0002f0	49	43	45	4f	00	00	00	00	00	00	41	08	22	00	00	10	ICE0A." 🔻
×																	Þ
Offset 0=0x0 Bits=01010111 Unsigned: B:87,W:10071,L:10071 ANSI / OVR / L Size: 1130544																	

Memory	Location

<u>Variable</u>

000200	start of tester header, each test is described in 50 bytes the elements of which are listed below as an offset from the start of the test description.
00-09	test name
0a	unit of measurement (e.g. V=Volts)
0b	scaling factor (0=pico, 3=nano, 6=micro, 9=mili etc.)
0c-27	unknown
28-30	bias(condition)1
28-2d	bias name
2e-2f	bias value
30	bias scaling factor
31	bias Unit
32-3b	bias2 (see above)
3c-45	bias3 (see above)
46-47	min limit value
48	unknown
49	min limit scaling factor
4a-4b	max limit value
4c	unknown
4d	max limit scaling factor

Where a test has no limits the min and max values are shown as 00 00 but where a test has only a min or a max limit the missing limit is shown as f1 d8 (two's compliment equivalent of -9999).

Data Section

(F:\ZXTI	N303	5CLF	P-9R	51W	OVE	N.1-1	L9.jdf] - F	rhed												X	
<u>File D</u> isk	<u>E</u> d	lit .	<u>V</u> iew	<u>0</u>	ptior	ns j	<u>R</u> egis	try	Boo	okma	arks	Mis	ic I	<u>H</u> elp								
🗅 🚅 层	1 3	<mark>%</mark> ⊑	6	3	64 (в	?			•												
000a20	01	00	00	00	06	00	00	80	00	00	14	00	ff	ff	10	0b		•••		ÿÿ		
000a30	ff	ff	10	07	00	00	10	08	01	00	10	0c	6e	03	10	0e	ÿÿ	• • •		n.		
000a40	9f	10	10	0d	dd	e0	10	0c	19	20	10	0c	ff	ff	10	05	Ý	à.,	• •	ÿÿ		
000a50	00	00	10	05	00	00	14	00	8e	04	11	0e	00	00	00	00		• • •				
000a60	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00		• • •				
000a70	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00		• • •				
000a80	00	00	00	00	00	00	00	00	00	00	00	00	c4	09	10	0b		• • •		Ä.		
000a90	02	00	00	00	06	00	00	80	00	00	14	00	ff	ff	10	0b		• • •		••ÿÿ		
000aa0	ff	ff	10	07	ff	ff	10	08	01	00	10	0c	1a	04	10	0e	ÿÿÿ	ÿ.,				
000ab0	fc	10	10	0d	6a	e0	10	0c	12	20	10	0c	ff	ff	10	05	üj	à.,	• •	••ÿÿ		
000ac0	00	00	10	05	00	00	14	00	a6	04	11	0e	00	00	00	00		• • •	. j.,			
000ad0	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00		• • •				
000ae0	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00	00		• • •				
000af0	00	00	00	00	00	00	00	00	00	00	00	00	c 4	09	10	0b		• • •		Ä.		
000b00	03	00	00	00	03	00	00	80	00	00	14	00	ff	ff	10	0b		• • •		ÿÿ		
000b10	fe	ff	10	07	ff	ff	10	08	0f	27	13	0c	00	00	00	00	þÿÿ	ÿ.	'			Ŧ
																					•	
Offset 2203	Offset 2203=0x89b Bits=00001100 Unsigned: B:12,W:9996,L:9996 ANSI / OVR / L Size: 1130544																					

Memory Location Variable

Starts immediately after test header section each device is described in 04 bytes for the device and 04 bytes for each test.

00-03	device number
04	bin number
07	pass/fail bit 00=pass, 80=fail
08-0b	result of test 1
08-09	value of test 1
0a	result flag 10=pass, 11=parametric fail, 13=out of range, 14= no measurement
0b	scaling factor

Repeat for remainder of tests and devices.